

BALLROOM

OF2-33: Synthesis of Impedance Matching Circuits Using Arbitrary Nonuniform Transmission Lines

A.H. Hamade, A.B. Kouki, F.M. Ghannouchi, Dept. of ECE, Ecole Polytech. de Montreal, Quebec, Canada

OF2-34: Characterization and Minimization of Mutual Coupling Between NLC-Fed Slot Antennas

Y. Qian, T. Itoh, EE Dept., UCLA, Los Angeles, CA

OF2-35: A New Broadband Coplanar Waveguide to Slotline Transition

K.-P. Ma, T. Itoh, EE Dept., UCLA, Los Angeles, CA

OF2-36: FDTD Investigation of Higher Order Mode Leakage from Three Dimensional Microstrip Line Structures

Z. Ma, E. Yamashita, Dept. of EE, Univ. of Electro-Communications, Tokyo, Japan

OF2-37: Scattering Parameters of Interdigital Microstrip Gap Under Laser Spot Illumination

Y. Horii, Fac. of Info., Kansai Univ., Osaka, Japan, M. Tsutsumi, Fac. of Eng. and Design, Kyoto Inst. of Tech., Kyoto, Japan

OF2-38: Measurements of Unloaded Q-Factor of Transmission Mode Dielectric Resonators

K. Leong, J. Mazierska, James Cook Univ. of N. Queensland, Dept. of ECE, Townsville, Australia, J. Krupka, Warsaw Univ. of Tech., Inst. of Opto. and Microelec., Warsaw, Poland

OF2-39: Image Observation of Pico Second Electrical Pulse by Scanning Optoelectronic Microscope

K. Takeuchi, A. Mizuhara, Teratec Corp., Tokyo, Japan

OF2-40: Visualisation of Portable Phone-User Interactions via NF Mapping on Mannequins and Volunteers

L. Alhonsou, D. Picard, J.C. Bolomey, Electromag. Dept., SUPELEC/ CNRS, Gif sur Yvette, France

OF2-41: Microscopic Observation of the Temperature Coefficient Distribution of Dielectric Material for Microwave Application Using Scanning Photothermal Dielectric Microscope

Y. Cho, T. Kasahara, Dept. of EE, Yamaguchi Univ., Ube, Japan, K. Fukuda, UBE Industries, Ltd., Ube, Japan

*OF2-42: Novel Methods of Measuring Impurity Levels in Liquid Tanks M. Weib, R. Knochel, Tech. Fak. der Christian-Albrechts-Univ. zu Kiel, Kiel, Germany**OF2-43: Network-Analyzer Self-Calibration with Four or Five Standards for the 15-Term Error-Model*

A. Gronefeld, B. Schiek, Inst. fur HFtechnik, Ruhr-Univ. Bochum, Bochum, Germany

OF2-44: Comparison of Coplanar Microprobes for On-Wafer Measurements at W-Band

A. Pham, J. Laskar, Georgia Inst. of Tech., Atlanta, GA, S. Basu, J. Pence, Cascade Microtech, Inc.

OF2-45: A Calibration Procedure for W-Band On-Wafer Testing

Y.-L. Kok, M. DuFault, T.-W. Huang, H. Wang, TRW, Redondo Beach, CA

OF2-46: A New Field-Probing Technique for Millimeter-Wave Components

A. Basu, T. Itoh, EE Dept., UCLA, Los Angeles, CA

OF2-47: A Membrane Quadrant Probe for R&D Applications

S. Basu, R. Gleason, Cascade Microtech, Inc., Beaverton, OR

OF2-48: A Known Good Die Testing of Wide S/C Band Power MMICs

S. Basu, E. Strid, Cascade Microtech Inc., Beaverton, OR, R. Finke, Lockheed Martin, Nashua, NH

OF2-49: Microstrip Ring Resonator as a Moisture Sensor for Wheat Grains

K.K. Joshi, Dept. of Elec., S.P. College, Pune, India, M. Abegaonkar, R.N. Karekar, R.C. Ayer, Dept. of Physics, Univ. of Poona, Pune, India

OF2-50: Measurement of Temperature Dependence of Relative Permittivity by the Cavity Perturbation Method

T. Takahashi, Y. Iijima, T. Miura, Materials Research Ctr., TDK Corp., Chiba, Japan

OF2-51: A Novel Time Domain Characterization Technique of Intermodulation in Microwave Transistors and Application to the Visualization of the Distortion of High Efficiency Power Amplifiers

D. Barataud, A. Mallet, J.P. Fraysse, F. Blache, M. Campovecchio, J.M. Nebus, J.P. Villotte, IRCOM, Limoges, France, J. Verspecht, Hewlett-Packard NMDG, Brussels, Belgium

OF2-52: The Improvement of the Digital Mapping Predistorter for Linear Transmitters

Q. Ren, I. Wolff, Dept. of EE, GM Univ. Duisburg, Duisburg, Germany

OF2-53: Sensitivity of Distortion Cancellation in Feedforward Amplifiers to Loops Imbalances

Y. K. G. Hau, V. Postoyalko, J. R. Richardson, Micro. & Terahertz Tech. Group, Dept. of EEE, Univ. of Leeds, Leeds, UK

OF2-54: FFT Windows for Intermodulation Analysis of Microwave Circuits from Transient Simulation

K. Gard, QUALCOMM Inc., San Diego, CA

OF2-55: Phase Compensation in an Optically Controlled Microwave Attenuator

H. Shimasaki, S. Matsuda, M. Tsutsumi, Faculty of Eng., Kyoto Inst. of Tech., Kyoto, Japan

OF2-56: Millimetre Wave Generation by Filtering the FM-IM Spectra of a Directly Modulated DFB Laser

K.E. Razavi, P.A. Davies, Opt. Comm. Lab., Univ. of Kent at Canterbury, Kent, UK

OF2-57: 40 GHz-Narrow Band Photoreceiver for Clock Recovery in 40 Gbit/s Optical Transmission Systems

A. Miras, E. Legros, L. Giraudet, S. Vuye, CNET-FT, Lab. de Bagneux, Bagneux, France

OF2-58: 10 Gb/s Clock Extraction and Data Regeneration Circuit Implemented with Phase-Locked Loop

T.W. Yoo, M.S. Park, Optical Transmission Section, Elec. & Telecomm. Research Inst., Taejeon, Korea

OF2-59: Synthesis of Amplitude Response of Optical Directional Coupler Modulators

S.W. Lovseth, C. Laliew, A. Gopinath, Univ. of Minnesota, Dept. of EE, Minneapolis, MN

OF2-60: A New Approach for Optical Millimeter Wave Generation Utilizing Locking Techniques

T. Berceci, Tech. Univ. of Budapest, Budapest, Hungary

OF2-61: Dual Mode Patch Superconductor Cavity Filters

X. Zhang, C. Wang, K.A. Zaki, Univ. of MD, EE Dept., College Park, MD, K.S. Harshvardhan, Neocera, Inc., Beltsville, MD

OF2-62: Large-Signal Design of MMMIC Ka-Band Power Amplifiers Based on Physical Models

A.D. Plews, C.M. Snowden, M.J. Howes, Dept. of EEE, Univ. of Leeds, Leeds, UK

OF2-63: Modeling and Characterization of Interconnects and IC Packages by FDTD 3D Simulation

M. Falconer, V. Tripathy, ECE, Oregon State Univ., Corvallis, OR

OF2-64: Full-Wave Investigation on the Curved Bonding Wire Interconnection by Using a Suitable FDTD Code

F. Alimenti, P. Mezzanotte, L. Roselli, Univ. of Perugia, Perugia, Italy

OF2-65: Measurements of Field Distributions and Scattering Parameters in Multiconductor Structures Using an Electric Field Probe

I. Wolff, Y. Gao, Dept. of EE, GM Univ. Duisburg, Duisburg, Germany